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Judul:
Defects in microelectronic materials and devices
Pengarang/Penulis:

Subjek:
Microelectronics -- Materials -- Testing; Metal oxide semiconductor field -- Effect transistors -- Testing; Integrated circuits -- Defects
Nomor Panggil:
621.381 DEF
Penerbitan:
CRC Press, Taylor & Francis Group

Link Terkait:
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